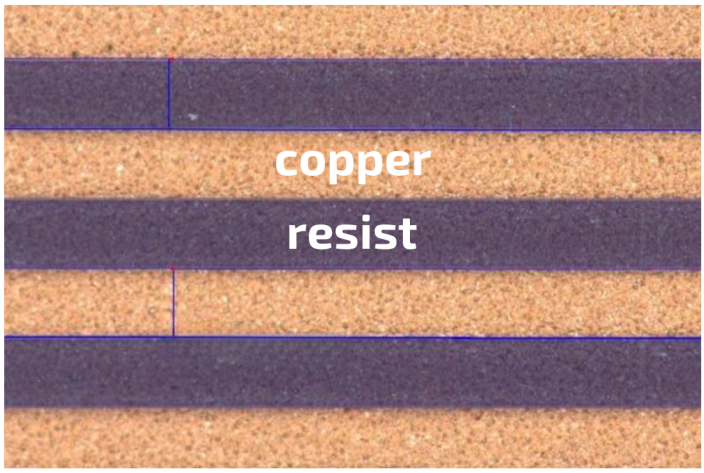
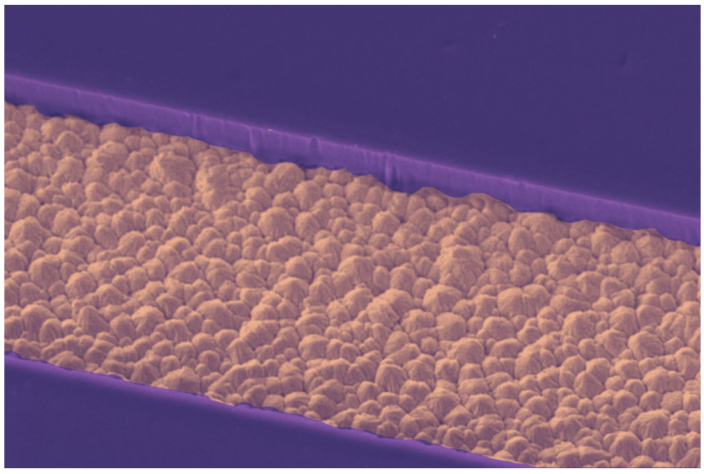
SEM Inner-Layer after Develop Unetched

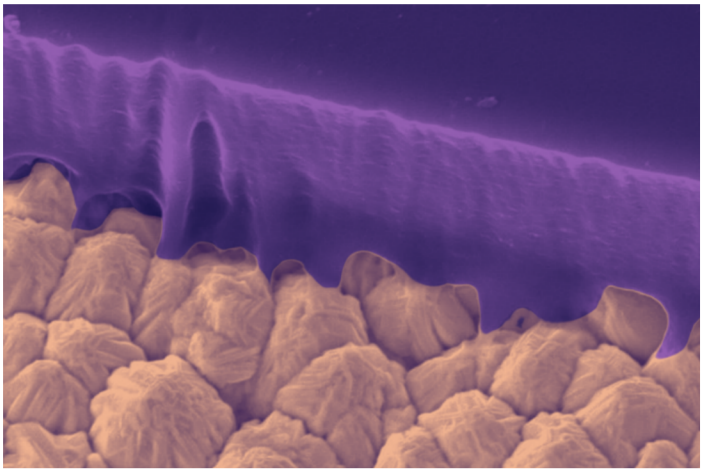
Scanning Electron Microscopy photos of what an imaged feature may look like at the photoresist level (colorized).



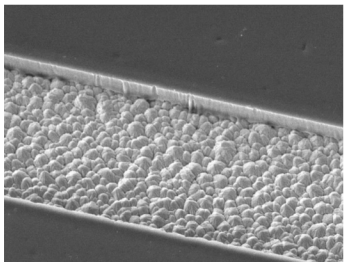
1x

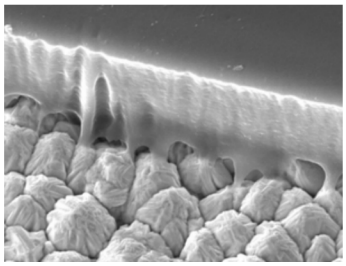


1000x



3000x





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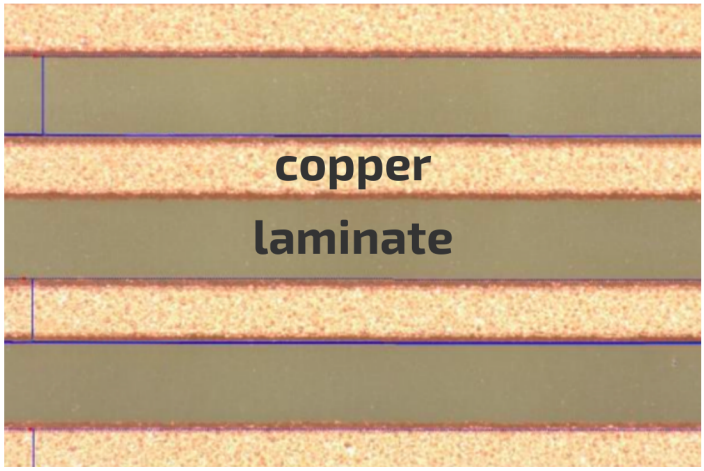
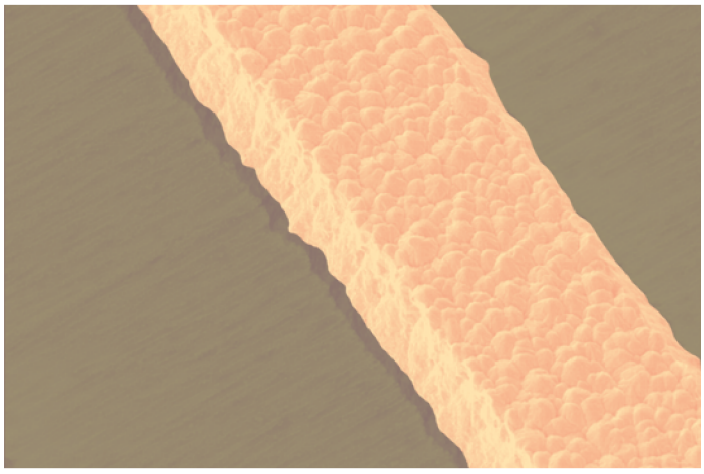
SEM Inner-Layer Etched

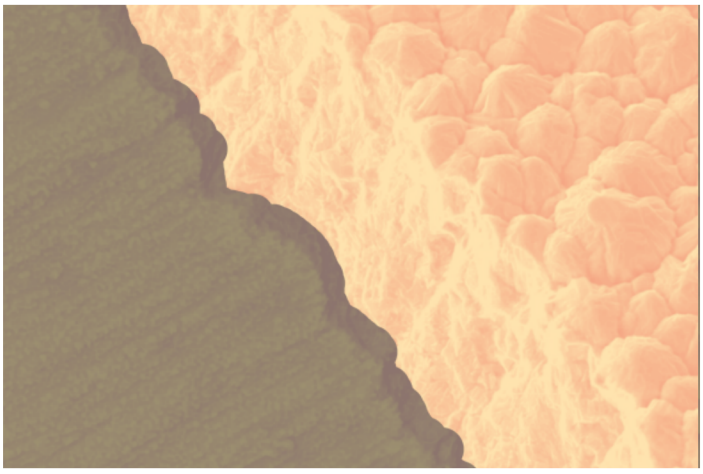
Scanning Electron Microscopy photos of what an imaged feature may look like at the etched level (colorized).



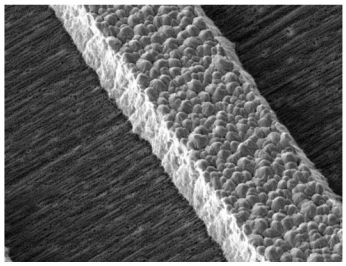
1x

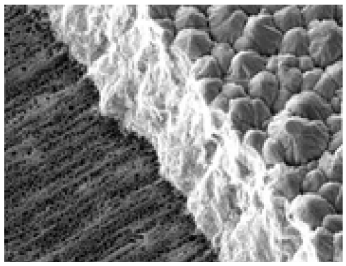


1000x



3000x





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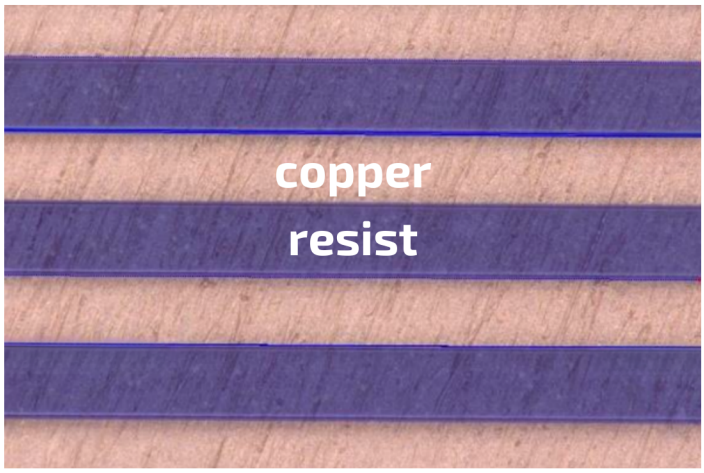
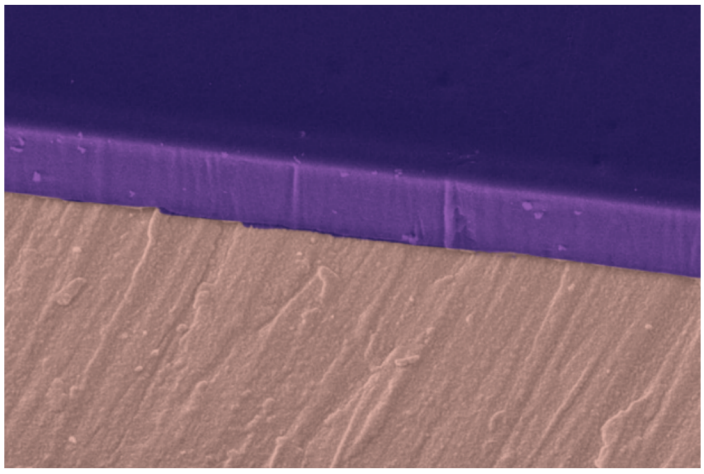
SEM Outer-Layer after Develop Unetched / Unplated

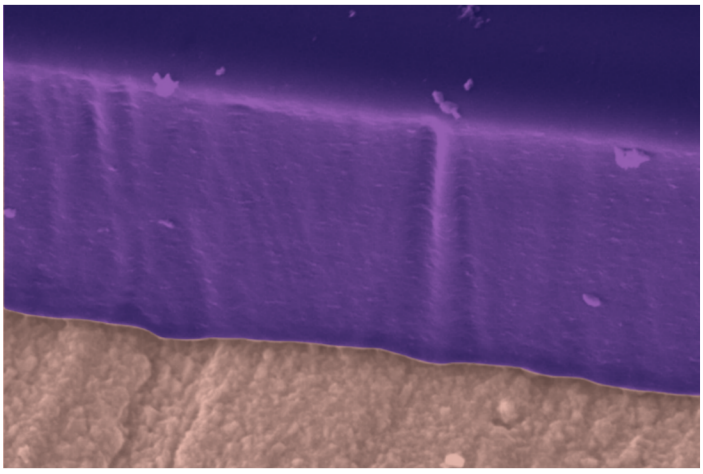
Scanning Electron Microscopy photos of what an imaged feature may look like at the photoresist level (colorized).



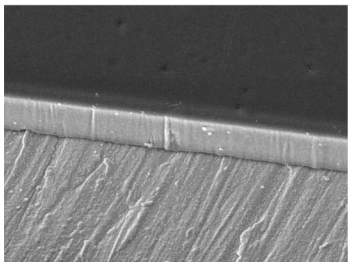
1x

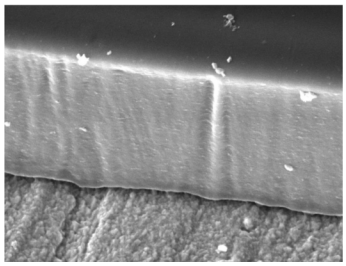


1000x



5000x





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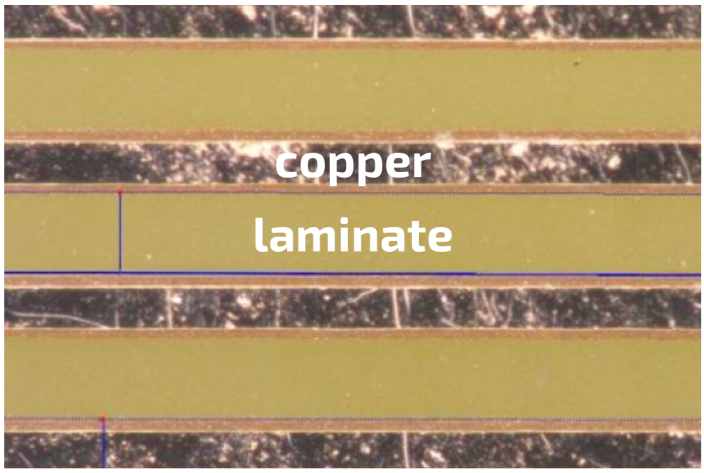
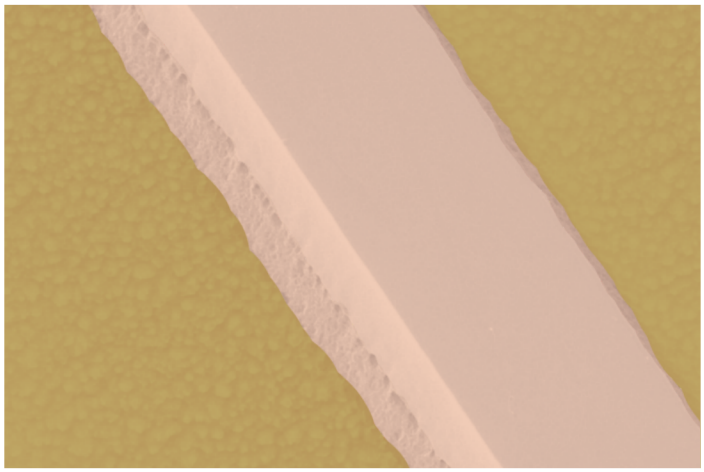
SEM Outer-Layer Etched

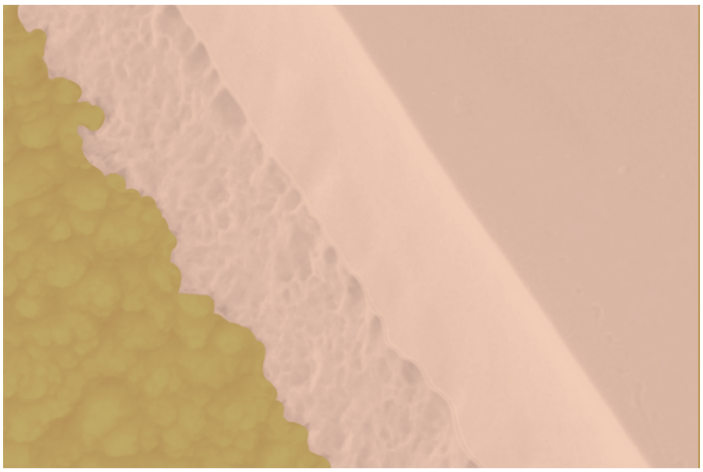
Scanning Electron Microscopy photos of what an imaged feature may look like at the etched level (colorized).



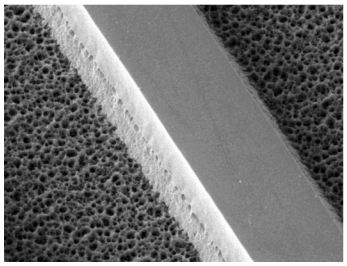
1x

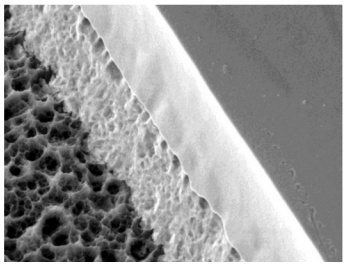


1000x



3000x





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